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U.S. Patent Documents

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Foreign Patent or Published Foreign Patent Application

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Non-Patent Literature Documents

Examiner Initials	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	OK	Ramesh, et al.; "Automatic Selection of Tuning Parameters for Feature Extraction Sequences"; June 21-23, 1994; IEEE; pp. 672-677; USA.
	OL	Niewczas, et al.; "A Pattern Matching Algorithm for Verification and Analysis of Very Large IC Layouts"; April 6-8, 1998; ACM; pp. 129-143; Monterey, California.

Examiner's Signature: /Barbara Burgess/   Date: 01/13/2010

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /B.B./